Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/511,678	NAKAYAMA ET AL.	
Examiner	Art Unit	

Son T. Nguyen

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	SEARCHED				
Class	Subclass	Date	Examiner		
119	253-256	3/30/2007	STN		
428	15-17 457				
	458				
446	153 156				
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427	304				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
text search, see printouts	3/30/2007	STN		
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